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**Frédéric Truchetet
Olivier Laligant**
Editors

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Contents

vii *Conference Committee*

SESSION 1 WAVELETS, FRAMES, SAMPLING, AND WATERMARKING

- 6763 03 **Accurate watermarking capacity evaluation** [6763-01]
O. Dumitru, M. Mitrea, F. Prêteux, ARTEMIS, GET/INT (France)

SESSION 2 SIGNAL AND IMAGE PROCESSING METHODS

- 6763 04 **A new generation of wavelet shrinkage: adaptive strategies based on composition of Lorentz-type thresholding and Besov-type non-threshold shrinkage** [6763-03]
L. Dechevsky, Narvik Univ. College (Norway); N. Grip, Luleå Univ. of Technology (Sweden); J. Gundersen, Narvik Univ. College (Norway)
- 6763 05 **Two-layer bandelets: algorithmic interpretation** [6763-04]
G. Lebrun, France Télécom Division Research and Development (France) and SIC (France); P. Carré, SIC (France); S. Pateux, France Télécom Division Research and Development (France)
- 6763 06 **Application of nonuniform Haar wavelets for solving integral and differential equations** [6763-05]
Ü. Lepik, Univ. of Tartu (Estonia)
- 6763 08 **Expo-rational spline multiwavelets: a first overview of definitions, properties, generalizations and applications** [6763-07]
L. Dechevsky, Narvik Univ. College (Norway); E. Quak, Tallinn Univ. of Technology (Estonia); B. Bang, A. Lakså, A. Kristoffersen, Narvik Univ. College (Norway)

SESSION 3 VIBRATION ANALYSIS

- 6763 09 **Determination of foundation characteristics of vibrating beams using wavelet transform and neural network** [6763-08]
H. Hein, Univ. of Tartu (Estonia)
- 6763 0A **Stationary wavelet transform for fault detection in rotating machinery** [6763-10]
S. Seker, E. Karatoprak, A. H. Kayran, T. Senguler, Istanbul Technical Univ. (Turkey)
- 6763 0B **Wavelet coherence analysis applied to laser vibrometry measurements** [6763-11]
G. Zauner, C. Ramsauer, G. Hendorfer, Upper Austria Univ. of Applied Sciences (Austria)

SESSION 4 TEXTURE ANALYSIS AND STATISTICS

- 6763 0D **Content adaptive wavelet based method for joint denoising of depth and luminance images** [6763-13]
L. Jovanov, N. Petrovic, A. Pižurica, W. Philips, Ghent Univ. (Belgium)
- 6763 0E **Multivariate indexing of multichannel images** [6763-14]
S. Sakji, A. Benazza-Benyahia, URISA, Ecole Supérieure des Communications de Tunis, Cité Technologique des Communications (Tunisia)
- 6763 0F **Line edge roughness measurement of nanostructures in SEM metrology by using statistically matched wavelet** [6763-15]
Y. Midoh, K. Nakamae, Osaka Univ. (Japan); H. Fujioka, Fukui Univ. of Technology (Japan)
- 6763 0G **Bayesian spherical wavelet shrinkage: applications to shape analysis** [6763-16]
X. Le Faucheur, B. Vidakovic, A. Tannenbaum, Georgia Institute of Technology (USA)

SESSION 5 RATIONAL WAVELETS

- 6763 0H **Design of orthonormal and overcomplete wavelet transforms based on rational sampling factors (Invited Paper)** [6763-18]
İ. Bayram, I. W. Selesnick, Polytechnic Univ. (USA)

SESSION 6 MULTICOMPONENTS ANALYSIS

- 6763 0J **Wavelet-based multicomponent image restoration** [6763-20]
A. Duijster, S. De Backer, P. Scheunders, Univ. of Antwerpen (Belgium)
- 6763 0K **Bayesian wavelet-based denoising of multicomponent images** [6763-21]
P. Scheunders, S. De Backer, Antwerp Univ. (Belgium); A. Pižurica, B. Huysmans, W. Philips, Ghent Univ. (Belgium)
- 6763 0L **Clouds removal from remotely sensed images by using a bandelet-based reconstruction technique** [6763-22]
A. Maalouf, P. Carré, B. Augereau, C. Fernandez-Maloigne, Univ. of Poitiers, Signal-Image-Communications Lab. (France)

SESSION 7 BIO-MEDICAL AND CHEMICAL APPLICATIONS

- 6763 0M **Computational algorithm for the filtrate and characterization of electrooculographics signals** [6763-23]
N. E. León-Martínez, M. J. Blanco-Díaz, A. Mendoza-Castellanos, Univ. Industrial de Santander (Colombia)
- 6763 0N **Prognostic 2.0: software tool for heart rate variability analysis and QT interval dispersion** [6763-24]
A. Mendoza, O. L. Rueda, Univ. Industrial de Santander (Colombia); L. X. Bautista, Univ. of Puerto Rico at Mayaguez (USA); V. E. Martinez, E. R. Lopez, M. F. Gomez, A. Alvarez, Univ. Industrial de Santander (Colombia)

- 6763 0O **A multi-resolution approach for optimal mass transport** [6763-25]
A. Dominitz, Technion (Israel); S. Angenent, Univ. of Wisconsin, Madison (USA);
A. Tannenbaum, Technion (Israel) and Georgia Institute of Technology (USA)
- 6763 0P **Detecting trace components in liquid chromatography/mass spectrometry data sets with two-dimensional wavelets** [6763-26]
D. C. Compton, R. R. Snapp, The Univ. of Vermont (USA)
- 6763 0Q **Wavelet-based isometric conversion between dimension and resolution and some of its applications** [6763-27]
L. Dechevsky, J. Gundersen, A. Kristoffersen, Narvik Univ. College (Norway)

POSTER SESSION

- 6763 0R **Wavelet transform to discriminate between crop and weed in agronomic images** [6763-28]
J. Bossu, C. Gée, ENESAD/DSI (France); F. Truchetet, Univ. de Bourgogne, CNRS (France)
- 6763 0S **Using technique of wavelet analysis for civil and industrial constructions fail-safety state evaluation** [6763-30]
S. V. Porshnev, A. V. Paranichev, Ural State Technical Univ. (Russia)
- 6763 0V **Performance evaluation of load forecasting models for energy purchase of power suppliers in the Amazonian region** [6763-34]
G. Conde, Á. L. de Santana, C. R. L. Francês, Federal Univ. of Pará (Brazil); C. A. Rocha, Univ. of the Amazon (Brazil); L. Rego, D. L. Cardoso, J. W. Costa, Univ. Federal do Pará (Brazil); V. Gato, Power Supplier of the State of Pará, CELPA (Brazil)
- 6763 0X **Shape-preserving wavelet approximation: state of the art and ongoing research** [6763-37]
L. Dechevsky, Narvik Univ. College (Norway)
- 6763 0Y **Nearly degenerating multigrid finite and boundary element methods versus lacunary wavelet-based methods of approximation** [6763-38]
L. Dechevsky, Narvik Univ. College (Norway)
- 6763 0Z **A biphasic scheme for edge detection** [6763-39]
O. Lalignant, F. Truchetet, Lab. Le2i, Univ. de Bourgogne (France)

Author Index

Conference Committee

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- 1 Wavelets, Frames, Sampling, and Watermarking
Paul Scheunders, Universiteit Antwerpen (Belgium)

- 2 Signal and Image Processing Methods
Ivan W. Selesnick, Polytechnic University (USA)
- 3 Vibration Analysis
William S. Hortos, Associates in Communication Engineering Research and Technology (USA)
- 4 Texture Analysis and Statistics
Akram Aldroubi, Vanderbilt University (USA)
- 5 Rational Wavelets
Frédéric Truchetet, Laboratoire Le2i, CNRS, Université de Bourgogne (France)
- 6 Multicomponents Analysis
Frédéric Truchetet, Laboratoire Le2i, CNRS, Université de Bourgogne (France)
- 7 Bio-medical and Chemical Applications
Gerald Zauner, FH OÖ Forschungs and Entwicklungs GmbH (Austria)